Se	arch No	ies

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/665,787	BUCHNER ET AL.	
Examiner	Art Unit	
Aung T. Win	2617	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
-	<u> </u>		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
searched by keywords	12/4/2006	ATW
discussed with Tommy Chin and John Peng for claims clarity	12/4/2006	ATW
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